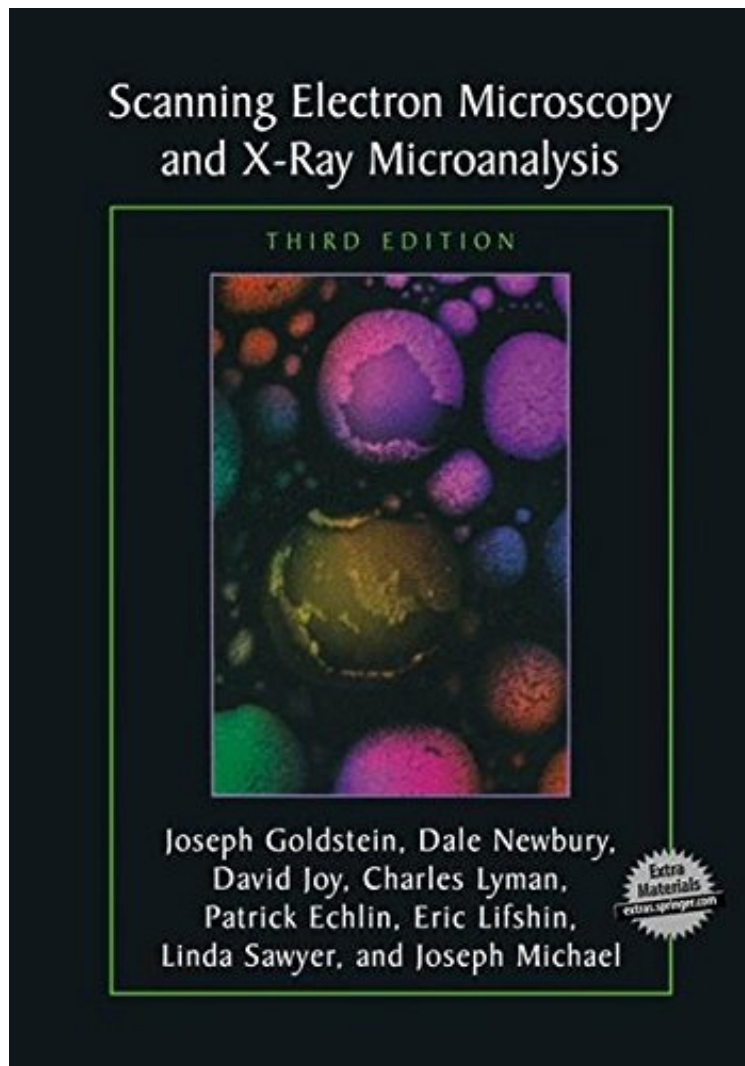


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Scanning Electron Microscopy and X-ray Microanalysis: Third Edition

Joseph Goldstein, Dale E. Newbury, David C. Joy, Charles E. Lyman, Patrick Echlin, Eric Lifshin, Linda Sawyer, J.R. Michael

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6 of 6 people found the following review helpful. The Bible of All Scanning Electron Microscopy Books By Phillip If you are like me and had to use a Scanning Electron Microscope or SEM, you want to start with the basics that everyone goes by. This book is a safe bet that most everyone knows about. Plus, it is written with very little background in the world of electron microscopy. Too many authors to list but it's wonderful that a lot of experts got together to present this material in clear, concise manner. Before you grab your solid-state physics book or check Wikipedia, just relax and page through it since this book pretty much makes it easy for you. Chapters are arranged by the following: What is SEM?, How SEM works?, and Why are we interested with SEM? That's the easiest way to explain rather than list all the chapters. If you have a specific question, you don't even have to read through the previous chapters (if you have rough understanding). The size of this book is a BIG PLUS. It's compact compared to the monstrous Transmission Electron Microscopy (TEM) book by Barry Carter which is another great reference. For this price, you would be lucky to find another good reference book under \$100 with such relevant information.

1 of 1 people found the following review helpful. Excellent so far. By TFM3 I'm reading this book and an older edition of the Reimer text for an independent study course in SEM. While I'm only three chapters into both texts, the Goldstein text seems more readable. I like the writing style, and it doesn't seem to sacrifice in any technical aspect. It is also very well illustrated. For a book about an imaging technology, this is obviously quite important. There are many instances where there are sets of images to compare the results achieved with varied operating parameters. The text is well organized. It begins with an assumption that you know some basic physics and chemistry, but doesn't require any background in microscopy. Both the Table of Contents and Index are detailed enough to enable specific searches for specific subject matter. This is a textbook I look forward to reading in the evening, and one that I look forward to finishing. It matches very well with the practical work I'm doing on the SEM.

This text provides students as well as practitioners with a comprehensive introduction to the field of scanning electron microscopy (SEM) and X-ray microanalysis. The authors emphasize the practical aspects of the techniques described. Topics discussed include user-controlled functions of scanning electron microscopes and x-ray spectrometers and the use of x-rays for qualitative and quantitative analysis. Separate chapters cover SEM sample preparation methods for hard materials, polymers, and biological specimens. In addition techniques for the elimination of charging in non-conducting specimens are detailed.

There is no other single volume that covers as much theory and practice of SEM or X-ray microanalysis as Scanning Electron Microscopy and X-ray Microanalysis, 3rd Edition does. It is clearly written ... well organized. ... This is a reference text that no SEM or EPMA laboratory should be without. (Thomas J. Wilson, Scanning, Vol. 27 (4), July/August, 2005) As the authors pointed out, the number of equations in the book is kept to a minimum, and important conceptions are also explained in a qualitative manner. A lot of very distinct images and schematic drawings make for a very interesting book and help readers who study scanning electron microscopy and X-ray microanalysis. The principal application and sample preparation given in this book are suitable for undergraduate students and technicians learning SEEM and EDS/WDS analyses. It is an excellent textbook for graduate students, and an outstanding reference for engineers, physical, and biological scientists. (Microscopy and Microanalysis, Vol. 9 (5), October, 2003) About the Author This text is written by a team of authors associated with SEM and X-ray Microanalysis Courses presented as part of the Lehigh University Microscopy Summer School. Several of the authors have participated in this activity for more than 30 years.